

L11 ANSWER 1 OF 5 CA COPYRIGHT 2008 ACS on STN  
ACCESSION NUMBER: 145:430085 CA <<LOGINID::20080108>>  
TITLE: Effects of SiN passivation by  
catalytic chemical vapor deposition on  
electrical properties of AlGa<sub>N</sub>/Ga<sub>N</sub> heterostructure  
field-effect transistors  
AUTHOR(S): Higashiwaki, Masataka; Onojima, Norio; Matsui,  
Toshiaki; Mimura, Takashi  
CORPORATE SOURCE: National Institute of Information and Communications  
Technology, Koganei, Tokyo, 184-8795, Japan  
SOURCE: Journal of Applied Physics (2006), 100(3),  
033714/1-033714/6  
CODEN: JAPIAU; ISSN: 0021-8979  
PUBLISHER: American Institute of Physics  
DOCUMENT TYPE: Journal  
LANGUAGE: English  
AB We investigated the effects of SiN passivation by  
catalytic chemical vapor deposition (Cat-CVD) on the elec.  
properties of AlGa<sub>N</sub>/Ga<sub>N</sub> heterostructure field-effect transistors. The  
two-dimensional electron d. (Ns) greatly increased after the Cat  
-CVD SiN deposition, and the tendency of the increase was enhanced with  
decreasing AlGa<sub>N</sub> barrier thickness. As a result of the large increase in  
Ns, the sheet resistance (Rsh) significantly decreased after the  
deposition, and it had low values of 320-460  $\Omega$ /box. for extremely  
thin AlGa<sub>N</sub> barriers of 4-10 nm. The increase in Ns showed little  
dependence on SiN thickness, indicating that the stress applied to the  
AlGa<sub>N</sub> barrier by SiN cannot be the origin of the increase. Cat  
-CVD SiN also improved the in-plane uniformity of mobility for extremely  
thin-barrier structures, which in turn improved the uniformity of Rsh.  
Moreover, we found that Cat-CVD was more effective than  
plasma-enhanced chemical vapor deposition in increasing Ns. A comparison of  
theor. calcns. and exptl. results indicated that these behaviors can be  
explained by a decrease in the AlGa<sub>N</sub> surface barrier height due  
to the SiN deposition.  
REFERENCE COUNT: 28 THERE ARE 28 CITED REFERENCES AVAILABLE FOR THIS  
RECORD. ALL CITATIONS AVAILABLE IN THE RE FORMAT

L11 ANSWER 2 OF 5 CA COPYRIGHT 2008 ACS on STN  
ACCESSION NUMBER: 142:422508 CA <<LOGINID::20080108>>  
TITLE: Gas sensor device  
INVENTOR(S): Sandvik, Peter Micah; Tilak, Vinayak; Tucker, Jesse;  
Weaver, Stanton Earl; Shaddock, David Mulford; Male,  
Jonathan Lloyd; Lemmon, John Patrick; Woodmansee, Mark  
Allen; Manivannan, Venkatesan; Haitko, Deborah Ann  
PATENT ASSIGNEE(S): General Electric Company, USA  
SOURCE: U.S. Pat. Appl. Publ., 14 pp.  
CODEN: USXXCO  
DOCUMENT TYPE: Patent  
LANGUAGE: English  
FAMILY ACC. NUM. COUNT: 1  
PATENT INFORMATION:

PATENT NO.	KIND	DATE	APPLICATION NO.	DATE
US 2005097941	A1	20050512	US 2003-706767	20031112
US 7053425	B2	20060530		
CA 2544939	A1	20050609	CA 2004-2544939	20041012
WO 2005052566	A2	20050609	WO 2004-US33506	20041012

WO 2005052566 A3 20050901

W: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW, RW: BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW, AM, AZ, BY, KG, KZ, MD, RU, TJ, TM, AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR, BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG

EP 1685394 A2 20060802 EP 2004-794773 20041012

R: AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT, IE, SI, FI, RO, CY, TR, BG, CZ, EE, HU, PL, SK

JP 2007512514 T 20070517 JP 2006-539502 20041012

PRIORITY APPLN. INFO.: US 2003-706767 A 20031112

WO 2004-US33506 W 20041012

AB A gas sensor device including a semiconductor substrate; one or more catalytic gate-electrodes deposited on a surface of the semiconductor substrate; one or more ohmic contacts deposited on the surface of the semiconductor substrate and a passivation layer deposited on at least a portion of the surface; wherein the semiconductor substrate includes a material selected from the group consisting of silicon carbide, diamond, Group III nitrides, alloys of Group III nitrides, zinc oxide, and any combinations thereof.

REFERENCE COUNT: 38 THERE ARE 38 CITED REFERENCES AVAILABLE FOR THIS RECORD. ALL CITATIONS AVAILABLE IN THE RE FORMAT

L11 ANSWER 3 OF 5 CA COPYRIGHT 2008 ACS on STN

ACCESSION NUMBER: 142:359639 CA &lt;&lt;LOGINID::20080108&gt;&gt;

TITLE: NH3 and urea in the selective catalytic reduction of NOx over oxide-supported copper catalysts

AUTHOR(S): Sullivan, James A.; Doherty, Julie A.

CORPORATE SOURCE: Dep. Chem., Univ. Coll. Dublin, Dublin, Ire.

SOURCE: Applied Catalysis, B: Environmental (2005), 55(3), 185-194

CODEN: ACBEE3; ISSN: 0926-3373

PUBLISHER: Elsevier B.V.

DOCUMENT TYPE: Journal

LANGUAGE: English

AB The temperature-programmed activity of a series of oxide-supported (TiO<sub>2</sub>, Al<sub>2</sub>O<sub>3</sub>,

and SiO<sub>2</sub>) Cu catalysts formed from two different Cu precursors [Cu(NO<sub>3</sub>)<sub>2</sub> and CuSO<sub>4</sub>] for the selective catalytic reduction of NOx using solns. of urea as a reductant have been determined. These activities are compared to those found using NH<sub>3</sub> as a reducing agent over the same catalysts in the presence of H<sub>2</sub>O, and it is found that catalysts that are active for the selective reduction of NOx with NH<sub>3</sub> are inactive for its reduction using solns. of urea. Poisoning of the surface by adsorbed H<sub>2</sub>O is not responsible for all of this decrease in activity, and it is postulated that the urea is not hydrolyzing to form NH<sub>3</sub> over the catalysts but rather is oxidizing to form N<sub>2</sub> or forming passivated layers of polymeric melamine complexes on the surface. The catalysts were characterized by temperature-programmed reduction, while

temperature-programmed desorption

and oxidation of NH<sub>3</sub> and temperature-programmed decomposition of urea are used to

characterize the interaction of both reductants with the various catalysts.

REFERENCE COUNT: 27 THERE ARE 27 CITED REFERENCES AVAILABLE FOR THIS RECORD. ALL CITATIONS AVAILABLE IN THE RE FORMAT

L11 ANSWER 4 OF 5 CA COPYRIGHT 2008 ACS on STN

ACCESSION NUMBER: 118:25597 CA <<LOGINID::20080108>>

TITLE: The effect of chromium in substrate of aluminized steel sheet on corrosion behavior under exhaust gas condensate in automotive muffler

AUTHOR(S): Higuchi, Seijun; Asakawa, Kenichi

CORPORATE SOURCE: Yawata Res. Dev. Lab., Nippon Steel Corp., Japan

SOURCE: Tetsu to Hagane (1992), 78(10), 1569-76

CODEN: TEHAA2; ISSN: 0021-1575

DOCUMENT TYPE: Journal

LANGUAGE: Japanese

AB The following are main results of investigation about the effect of chromium of substrate on corrosion behavior of aluminized steel sheets in neutral or weakly alkaline solution of  $\text{NH}_4^+$  which contains  $\text{Cl}^-$ ,  $\text{SO}_4^{2-}$ ,  $\text{CH}_3\text{COO}^-$  and  $\text{HCOO}^-$  which are found in exhaust gas condensate. Corrosion resistance of aluminized steel is enhanced if the substrate contains more than 5 wt% of chromium. One reason is cathodic corrosion protection of a coating layer at coating defects, and the other is the improvement in corrosion resistance of base steel itself. The improvement in corrosion resistance of base steel is due to the covering effect of  $\text{Cr}_2\text{O}_3$  oxide film on steel in the ambient air and the effect of being passivated in each solution which contains  $(\text{NH}_4)_2\text{SO}_4$ ,  $\text{CH}_3\text{COONH}_4$ , or  $\text{HCOONH}_4$  individually.. Substrate chromium steel has more stable cathodic protection than low carbon steel due to these films on the surface. The effect grows as chromium content increases and is remarkable especially in case of 11 weight% Cr steel. In the synthetic condensate solution including various ion passivation is generated on the surface of 11 weight% Cr steel even in presence of substantial  $\text{Cl}^-$  ion. Therefore an aluminized steel sheet with substrate containing more than 11 wt% Cr shows practically excellent corrosion performance.

L11 ANSWER 5 OF 5 CA COPYRIGHT 2008 ACS on STN

ACCESSION NUMBER: 111:185894 CA <<LOGINID::20080108>>

TITLE: Multilayer ceramic coatings from metal oxides and hydrogen silsesquioxane resin ceramified in ammonia

INVENTOR(S): Haluska, Loren Andrew; Michael, Keith Winton; Tarhay, Leo

PATENT ASSIGNEE(S): Dow Corning Corp., USA

SOURCE: Eur. Pat. Appl., 11 pp.

CODEN: EPXXDW

DOCUMENT TYPE: Patent

LANGUAGE: English

FAMILY ACC. NUM. COUNT: 1

PATENT INFORMATION:

PATENT NO.	KIND	DATE	APPLICATION NO.	DATE
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EP 323186	A2	19890705	EP 1988-312293	19881223
EP 323186	A3	19900919		
EP 323186	B1	19940316		
R: DE, FR, GB, NL				
US 4849296	A	19890718	US 1987-138744	19871228

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CA 1323529	C	19931026	CA 1988-583713	19881122
JP 01204432	A	19890817	JP 1988-320735	19881221
JP 06103690	B	19941214		
JP 07025606	A	19950127	JP 1990-800027	19900417
JP 08005656	B	19960124		

PRIORITY APPLN. INFO.:

US 1987-138744 A 19871228

AB Mixts. of H silsesquioxane resin and metal oxide precursors such as acyloxy and alkoxy compds. of Al, Zr, and Ti can be coated on substrates and subsequently ceramified at low temperature in the presence of NH<sub>3</sub>, with or without Pt or Rh catalysis, to form a nitrided ceramic coating on the surface of the substrate. The nitrided coatings produced are useful as interlevel dielec. films or for planarizing and protecting the surface of electronic devices. For further surface protection, overcoating the nitrided coating with an addnl. layer of a passivating ceramic material and a top layer of a barrier ceramic material is also described.

=> d his

(FILE 'HOME' ENTERED AT 10:50:23 ON 08 JAN 2008)

FILE 'CA' ENTERED AT 10:50:30 ON 08 JAN 2008

L1 9396 S PICOLINE? AND PREP?  
L2 425713 S AMMONIA OR NH<sub>4</sub>  
L3 606 S L1 AND L2  
L4 175 S TITANIUM-SILICATE CAT?  
L5 1 S L4 AND L3  
L6 1 S L4 AND PASSIVAT?  
L7 42 S SURFACE AND PASSIVA? AND TITANI? AND SILIC? AND CAT?  
L8 1 S L7 AND PICOLIN?  
L9 41 S L7 NOT L8  
L10 306054 S L9 AND AMMONIA OR NH<sub>4</sub> OR NH  
L11 5 S L10 AND L9

=> s selective passivation

417158 SELECTIVE

41148 PASSIVATION

L12 22 SELECTIVE PASSIVATION  
(SELECTIVE(W) PASSIVATION)

=> d his

(FILE 'HOME' ENTERED AT 10:50:23 ON 08 JAN 2008)

FILE 'CA' ENTERED AT 10:50:30 ON 08 JAN 2008

L1 9396 S PICOLINE? AND PREP?  
L2 425713 S AMMONIA OR NH<sub>4</sub>  
L3 606 S L1 AND L2  
L4 175 S TITANIUM-SILICATE CAT?  
L5 1 S L4 AND L3  
L6 1 S L4 AND PASSIVAT?  
L7 42 S SURFACE AND PASSIVA? AND TITANI? AND SILIC? AND CAT?  
L8 1 S L7 AND PICOLIN?  
L9 41 S L7 NOT L8  
L10 306054 S L9 AND AMMONIA OR NH<sub>4</sub> OR NH  
L11 5 S L10 AND L9  
L12 22 S SELECTIVE PASSIVATION

10/806061

=> s l12 and l4

L13 0 L12 AND L4

=> s select? passivat?

1319463 SELECT?

50759 PASSIVAT?

L14 42 SELECT? PASSIVAT?

(SELECT? (W) PASSIVAT?)

=> s l14 and l4

L15 0 L14 AND L4

=> s l1 and l14

L16 0 L1 AND L14

=> d his

(FILE 'HOME' ENTERED AT 10:50:23 ON 08 JAN 2008)

FILE 'CA' ENTERED AT 10:50:30 ON 08 JAN 2008

L1 9396 S PICOLINE? AND PREP?

L2 425713 S AMMONIA OR NH4

L3 606 S L1 AND L2

L4 175 S TITANIUM-SILICATE CAT?

L5 1 S L4 AND L3

L6 1 S L4 AND PASSIVAT?

L7 42 S SURFACE AND PASSIVA? AND TITANI? AND SILIC? AND CAT?

L8 1 S L7 AND PICOLIN?

L9 41 S L7 NOT L8

L10 306054 S L9 AND AMMONIA OR NH4 OR NH

L11 5 S L10 AND L9

L12 22 S SELECTIVE PASSIVATION

L13 0 S L12 AND L4

L14 42 S SELECT? PASSIVAT?

L15 0 S L14 AND L4

L16 0 S L1 AND L14

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10/806061

ACCESSION NUMBER: 142:113907 CA  
TITLE: Catalytic process for the production of pyridine and  
picolines from ammonia and carbonyl  
compounds  
INVENTOR(S): Kumar, Rajiv; Joshi, Praphulla Narahar; Chapekar,  
Gopal Moreshwar; Niphadkar, Prashant Suresh; Agarwal,  
Ashutosh; Verma, Pradeep Kumar; Singh, Kumar Samir  
PATENT ASSIGNEE(S): Council of Scientific and Industrial Research, India;  
Jubilant Organosys Ltd.  
SOURCE: PCT Int. Appl., 17 pp.  
CODEN: PIXXD2  
DOCUMENT TYPE: Patent  
LANGUAGE: English  
FAMILY ACC. NUM. COUNT: 1  
PATENT INFORMATION:

PATENT NO.	KIND	DATE	APPLICATION NO.	DATE
WO 2005000816	A1	20050106	WO 2003-IN465	20031231
W:	AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, UZ, VC, VN, YU, ZA, ZM, ZW			
RW:	BW, GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW, AM, AZ, BY, KG, KZ, MD, RU, TJ, TM, AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO, SE, SI, SK, TR, BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG			
US 2005131235	A1	20050616	US 2003-731440	20031210
AU 2003300721	A1	20050113	AU 2003-300721	20031231
EP 1648869	A1	20060426	EP 2003-817293	20031231
EP 1648869	B1	20071107		
R:	AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT, IE, SI, LT, LV, FI, RO, MK, CY, AL, TR, BG, CZ, EE, HU, SK			
AT 377587	T	20071115	AT 2003-817293	20031231
PRIORITY APPLN. INFO.:			IN 2003-DE853	A 20030627
			WO 2003-IN465	W 20031231

OTHER SOURCE(S): CASREACT 142:113907

AB A process for the prepn. of pyridine and/or picolines  
(e.g., a mixture of  $\alpha$ -picoline and  $\gamma$ -picoline  
) is described which comprises contacting a mixture of a carbonyl compound  
(e.g., acetaldehyde) with ammonia in the presence of a  
surface-passivated titanium silicate catalyst  
in gas phase at 300-500°/1-10 bar, a gas space velocity of 300-3000  
h-1, condensing and separating the products by conventional methods and if  
desired, further purifying the product using conventional methods.

REFERENCE COUNT: 3 THERE ARE 3 CITED REFERENCES AVAILABLE FOR THIS  
RECORD. ALL CITATIONS AVAILABLE IN THE RE FORMAT.